Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/678,313	TSUCHIYA, HITOSHI	
Examiner	Art Unit	
Toi Duona	2971	

SEARCHED						
Cla	ass	Subclass	Da	te	Exan	niner
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		114				
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		121				
		132				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (US PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM TDB) see search history printout	11/26/2006	TD
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